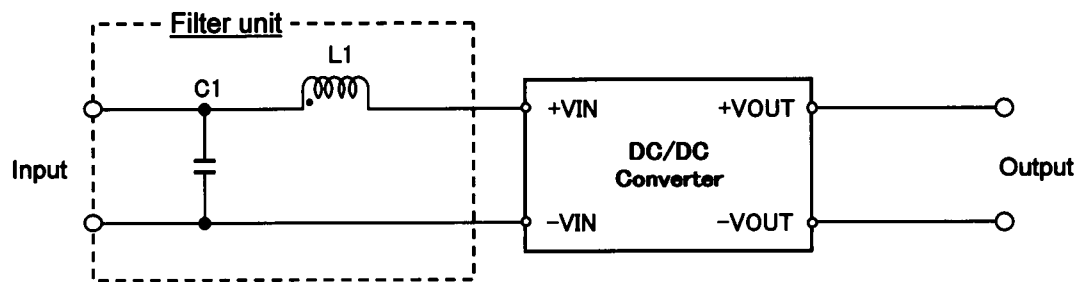


No.	Test item	Test conditions	Conditions of Acceptability	Result
1	Line conduction 雑音端子電圧	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ 周囲温度 $25 \pm 10^{\circ}\text{C}$ (4) Testing circuitry Fig.1 測定回路 図1	(1) Meets the undermentioned standard. VCCI classA CISPR11 classA, EN55011-A 下記規格に準拠していること VCCI classA CISPR11 classA, EN55011-A	OK
2	Radiated emission 放射電界強度	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ 周囲温度 $25 \pm 10^{\circ}\text{C}$ (4) Testing circuitry Fig.2 測定回路 図2	(1) Meets the undermentioned standard. VCCI classA CISPR11 classA, EN55011-A 下記規格に準拠していること VCCI classA CISPR11 classA, EN55011-A	OK
3	Static electricity immunity test (IEC61000-4-2) 静電気放電イミュニティ試験	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ 周囲温度 $25 \pm 10^{\circ}\text{C}$ (4) Contact discharge voltage Input, Output $\pm 8\text{kV}$ (Level 4) 印加電圧 入力・出力 $\pm 8\text{kV}$ (Level 4) (5) Testing circuitry Fig.1 測定回路 図1	(1) The power supply is not stop. 停止しないこと (2) Circuit does not malfunction. 誤動作のないこと (3) No abnormality of the insulation destruction etc. 絶縁破壊など故障がないこと (4) Parts are no damaged. 部品の故障がないこと	OK
4	Radiated, radio-frequency, electromagnetic field immunity test (IEC61000-4-3) 放射性無線周波電磁界 イミュニティ試験	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ 周囲温度 $25 \pm 10^{\circ}\text{C}$ (4) Testing field strength 10V/m (Level 3) 電界強度 10V/m (Level 3) (5) Testing circuitry Fig.3 測定回路 図3	(1) No protection circuit failure. 保護回路の故障がないこと (2) No output voltage drop with control circuit failure. 出力電圧の低下がないこと (3) No any other function failure 故障がないこと	OK
5	Electrical fast transient/ burst immunity test (IEC61000-4-4) 電氣的ファーストランジェント バーストイミュニティ試験	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ 周囲温度 $25 \pm 10^{\circ}\text{C}$ (4) Test peak voltage $\pm 4\text{kV}$ (Level 4) 印加電圧 $\pm 4\text{kV}$ (Level 4) (5) Testing circuitry Fig.1 測定回路 図1	(1) No protection circuit failure. 保護回路の故障がないこと (2) No output voltage drop with control circuit failure. 出力電圧の低下がないこと (3) No any other function failure 故障がないこと	OK
6	Surge immunity test (IEC61000-4-5) サージイミュニティ試験	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ 周囲温度 $25 \pm 10^{\circ}\text{C}$ (4) Test voltage 印加電圧 Line to line $\pm 2\text{kV}$ (Level 3) (5) Testing circuitry Fig.4 測定回路 図4	(1) The power supply is not stop. 停止しないこと (2) Circuit does not malfunction. 誤動作のないこと (3) No abnormality of the insulation destruction etc. 絶縁破壊など故障がないこと (4) Parts are no damaged. 部品の故障がないこと	OK

Approved : Isao Yasuda
Isao Yasuda

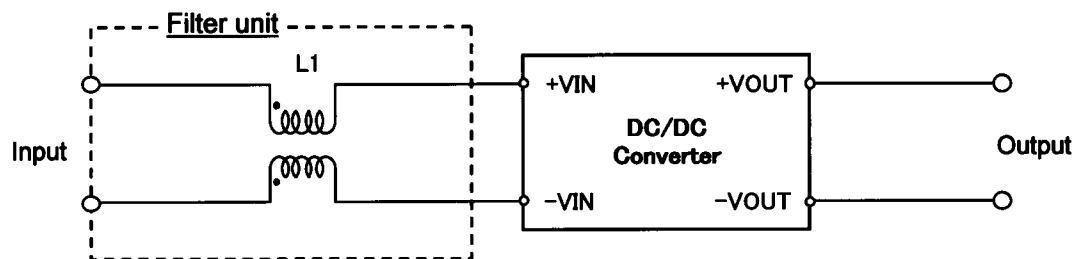
Prepared : Toshiyuki Tsuri
Toshiyuki Tsuri

○EMI/EMS testing circuitry



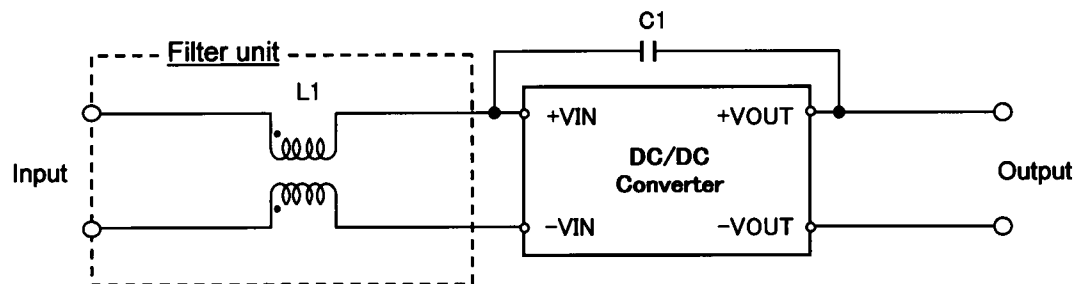
C1 : 1 μ F 100V Ceramic capacitor
L1 : 1 μ H 2.4A Inductor (C4-K1.8R 1R0 MITSUMI) or equivalent.

Fig.1 Testing circuitry



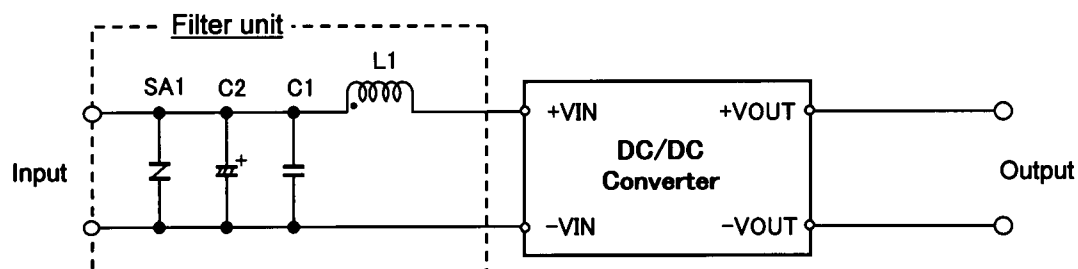
L1 : ZJYS51R5-2P TDK or equivalent.

Fig.2 Testing circuitry



L1 : ZJYS51R5-2P TDK or equivalent.
C1 : 1000pF 630V Ceramic capacitor

Fig.3 Testing circuitry



C1 : 1 μ F 100V Ceramic capacitor
C2 : 330 μ F 100V Electric capacitor
L1 : 1 μ H 2.4A Inductor (C4-K1.8R 1R0 MITSUMI) or equivalent.
SA1 : ERZV10D101 PANASONIC

Fig.4 Testing circuitry